Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/583,200	FIKES ET AL.
Examiner	Art Unit

1644

Ron Schwadron, Ph.D.

	SEAR	CHED	
Class	Subclass	Date	Examiner
530	324-328	3/5/	R
	350,828 806 185.1	7	B
424		9	<i>V)</i>
	277.1)
514	12-15	b	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Parent applications, MEDICIWE (BIFOTECH, West 201,	3/5/06	R B	
Gooble SEQ IV # 22 See enclosen Scarch Strategy			
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